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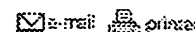
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 Photonics Technology Letters, IEEE
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 Moazzami, R.; Hu, C.;
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 Jianyao Chen; Ram, R.J.; Helkey, R.;
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| <input type="checkbox"/> | <p>7. Corrections to "Modeling of polarization mode competition in fiber DFB lasers"
 Ronnekleiv, E.; Zervas, M.N.; Kringlebotn, J.T.;
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Volume 35, Issue 7, July 1999 Page(s):1097 - 1100

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- ☐ 1. **Unit level predicted yield: a method of identifying high defect density die at wafer sort**
Miller, R.B.; Riordan, W.C.;
Test Conference, 2001. Proceedings. International
30 Oct.-1 Nov. 2001 Page(s):1118 - 1127
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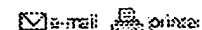


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 Van der Pol, J.A.; Ooms, E.R.; Van 't Hof, T.; Kuper, F.G.;
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- ☐ 2. **Reliability, test, and I_{DDQ} measurements**
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- ☐ 3. **Forecasting field failure rate**
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19th IEEE VLSI Test Symposium p. 0326

Burn-In Failures and Local Region Yield: An Integrated Yield-Reliability Model

Thomas S. Barnett, Auburn University
Adit D. Singh, Auburn University
Victor P. Nelson, Auburn University

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Abstract

Defects have long been known to cluster on semiconductor wafers. Recent research has shown that this fact may be exploited to produce die of high reliability, (i.e. decreased infant mortality), by sorting die into bins based on how many of their neighbors test faulty. Die that test good at wafer probe, yet come from neighborhoods with many faulty die, have a higher incidence of infant mortality failure than die from neighborhoods with few faulty die. Analysis of burn-in results from the SEMATECH test methods experiment [2] suggests that such a binning approach has the potential to isolate a high quality bin that displays very few burn-in failures. This paper presents the first analytical model that quantifies the reliability improvement one might expect when binning die based on local region yield.

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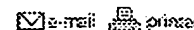


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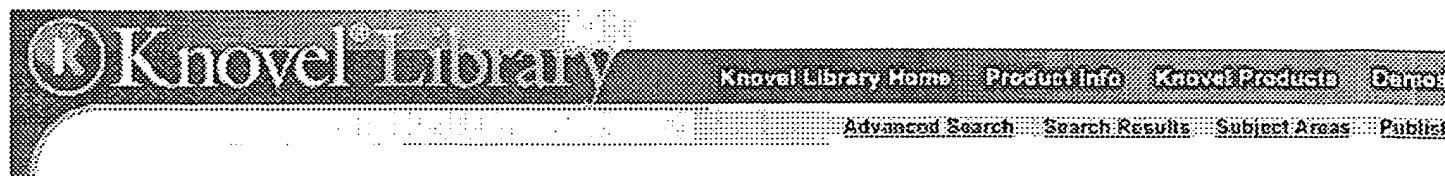
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Barnett, T.S.; Singh, A.D.; Nelson, V.P.;
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Physical & Failure Analysis of Integrated Circuits, 1997., Proceedings of the 1997 6th International Symposium on
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Van der Pol, J.A.; Ooms, E.R.; Van 't Hof, T.; Kuper, F.G.;
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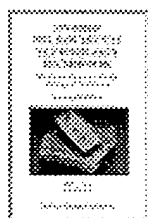
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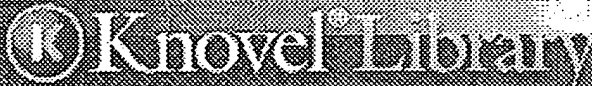
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